

 <p>U.S. Department of Commerce, Patent and Trademark Office</p> <p>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</p> <p>(Use several sheets if necessary)</p>	Application No.:	10/731,991
	Filing Date:	December 9, 2003
	First Named Inventor:	Peter G. Borden
	Group Art Unit:	2858
	Examiner Name:	Unknown
	Confirmation No.:	5839
Attorney Docket No.:	00849402USA BX17-1D	

U.S. Patent Documents							
*Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
IA	1.	4,873,434	10/10/89	See et al.	250	235	
	2.	6,541,747 B1	4/1/03	Kikuchi et al.	250	201	
	3.	2002/0167326 A1	11/14/02	Borden et al.	324	752	
	4.	2002/0105636 A1	8/8/02	Okawauchi	356	237	
	5.	5,530,550	6/25/96	Nikoonahad et al.	356	375	
	6.	5,610,718	3/11/97	Sentoku et al.	356	363	
	7.	4,758,092	7/19/88	Heinrich et al.	356	364	
	8.	6,411,389	6/25/02	Rushford	356	492	
IA	9.	6,072,179	6/6/00	Paniccia et al.	250	341	
Foreign Patent Documents							
		Document	Date	Country	Class	Subclass	Translation Yes No
IA	10.	0 566 217 A3	0 566 217 A3 12/93	EP	G01B	11/06	X
	11.	3158766	3158766 7/91	JP	G01R	19/00	X
	12.	0 313 681	0 313 681 5/89	EP	G03F	9/00	X
	13.	02102404	2102404 4/90	JP	G01B	11/24	X
IA	14.	2000021748	2000021748 1/00	JP	H01L	21/027	X
Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)							
IA	15.	H.K. Heinrich et al., "Picosecond Backside Optical Detection of Internal Signals in Flip-Chip Mounted Silicon VLSI Circuits", Microelectronic Engineering 16 (1992) March, pp 313-324					
	16.	Chung Wah See and Mehdi Vaez-iravani, "Differential amplitude scanning optical microscope: theory and applications", Applied Optics Vol. 27, No. 13, July 1, 1988, pp 2786-2792					
	17.	ISR PCT/US04/040969, International filing date 08/12/04					
	18.	PCT/US04/040969 Written Opinion, International filing date 08/12/04					
	19.	ISR PCT/US04/041256, International filing date 08/12/04					
IA	20.	PCT/US04/041256 Written Opinion, International filing date 08/12/04					

Examiner:	/Isiaka Akanbi/	Date Considered:	05/11/2006
<p>* Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication with applicant.</p>			